

# CMOS Delay-2 (H.2)

## Logical Effort

20160826

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Based on

Uyemura

Introduction to VLSI Circuits and Systems

Weste

CMOS VLSI Design

# Logical Effort Techniquis

shows how many stages of logic are required  
for the fastest implementation  
of any given logic function

Scaling of logic cascades  
Characterize logic gates & their interaction  
to provide techniques to minimize the delay

<high speed chains>

estimate

\* delays through logic cascades

\* scaling information

for minimum delay designs

the logical effort  $g$

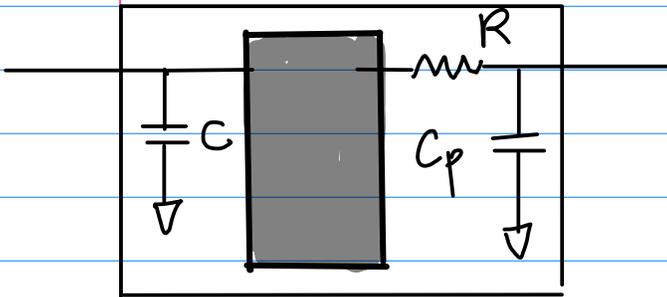
referenced to the 1X reference inverter

with input capacitance  $C_{ref}$   
and transistor resistance  $R_{ref}$

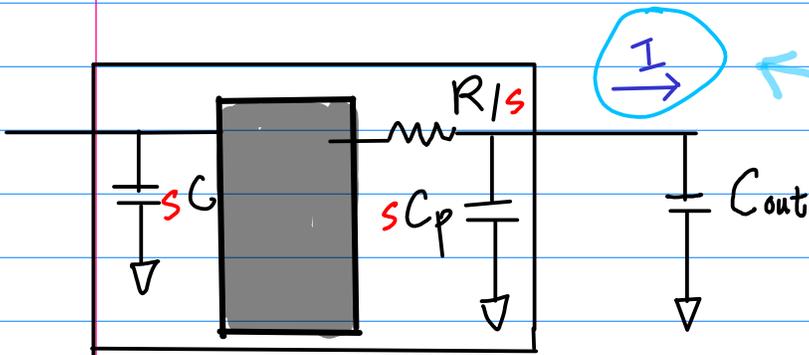
# Scale for the same current $I$

as that of the ref inverter

arbitrary gate

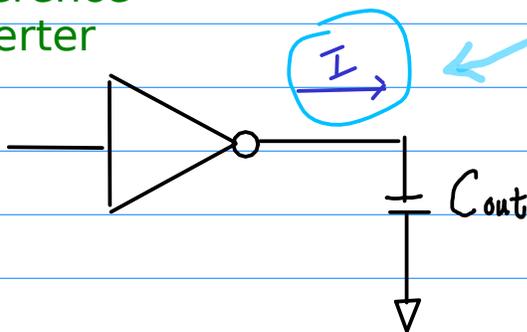


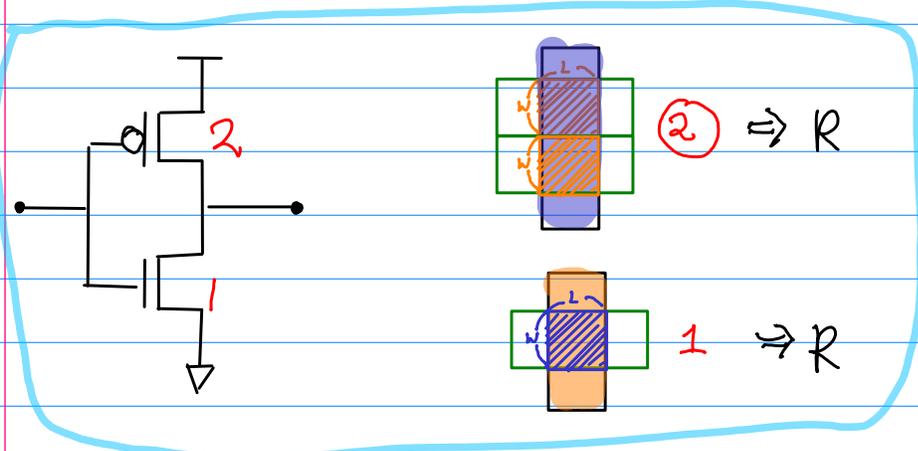
make it bigger by a factor of  $S$



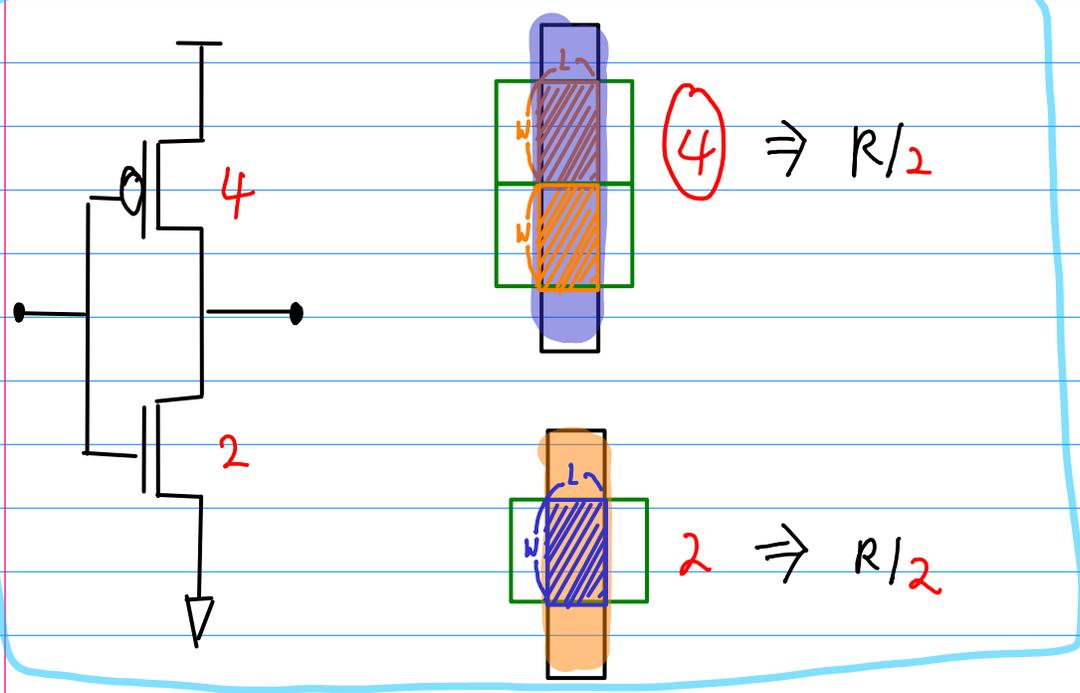
to deliver the same current as the reference inverter does

reference inverter





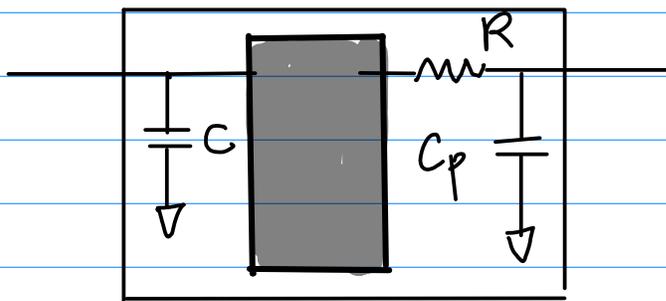
Scaling Factor  
 $S = 2$



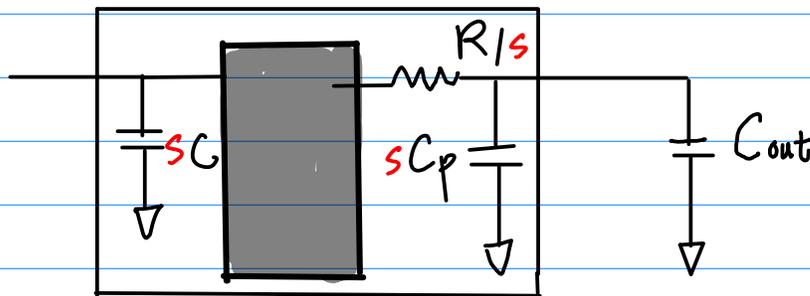
# Scaling Effects

			After scaling by $S$
	$R$	$\longrightarrow$	$\frac{R}{S}$
gate	$\hat{C}$	$\longrightarrow$	$S \hat{C}$
parasitic	$C_p$	$\longrightarrow$	$S C_p$

arbitrary gate

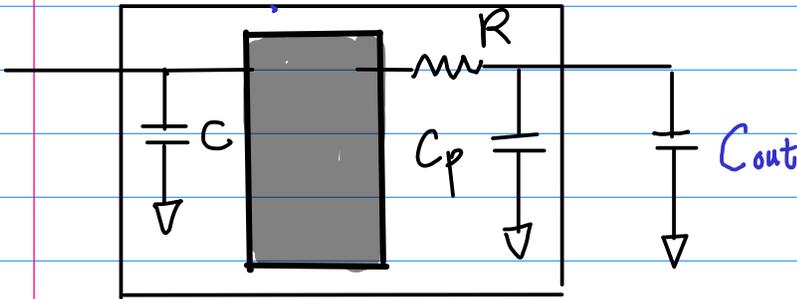


$\Downarrow$  scale  $S$



# delay proportional to time constant

arbitrary gate

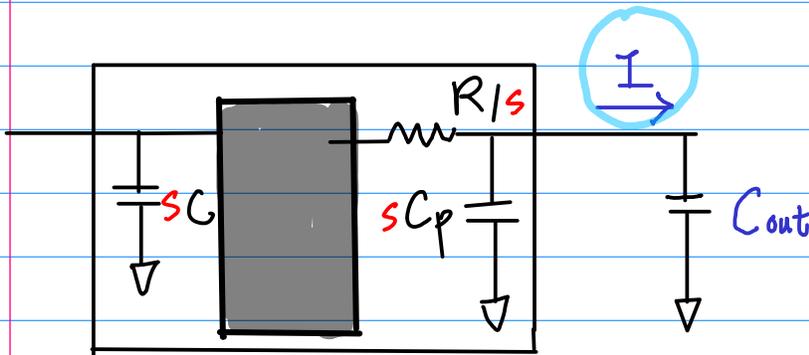


$$\text{delay} \propto RC$$

$$R = R$$

$$C = (C_p + C_{out})$$

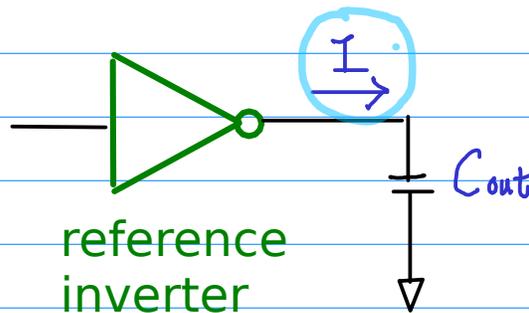
↓ scale (s)  
to get the same I



$$\text{delay} \propto R'C'$$

$$R' = R/s$$

$$C' = (sC_p + C_{out})$$



$$d \propto R C_p + R C_{out}$$

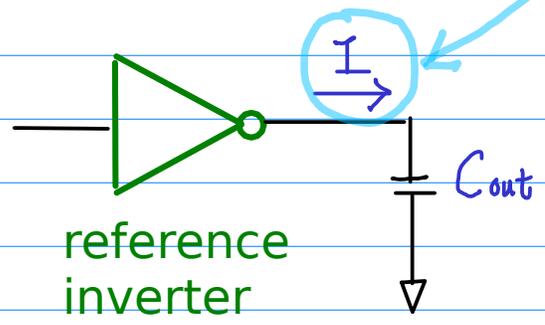
$$= R(C_p + C_{out})$$

↓ scale (s)  
to get the same I

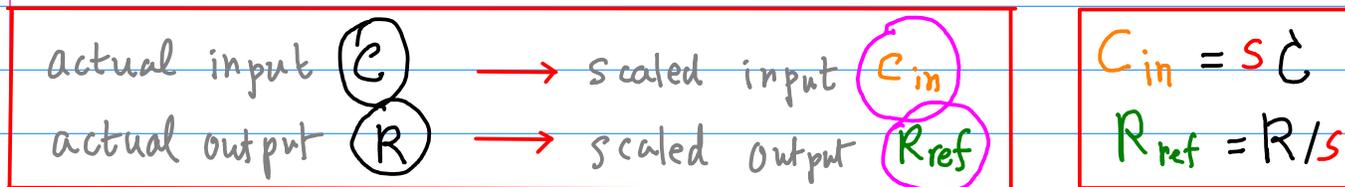
(make it bigger)

$$d \propto R C_p + \frac{R}{s} C_{out}$$

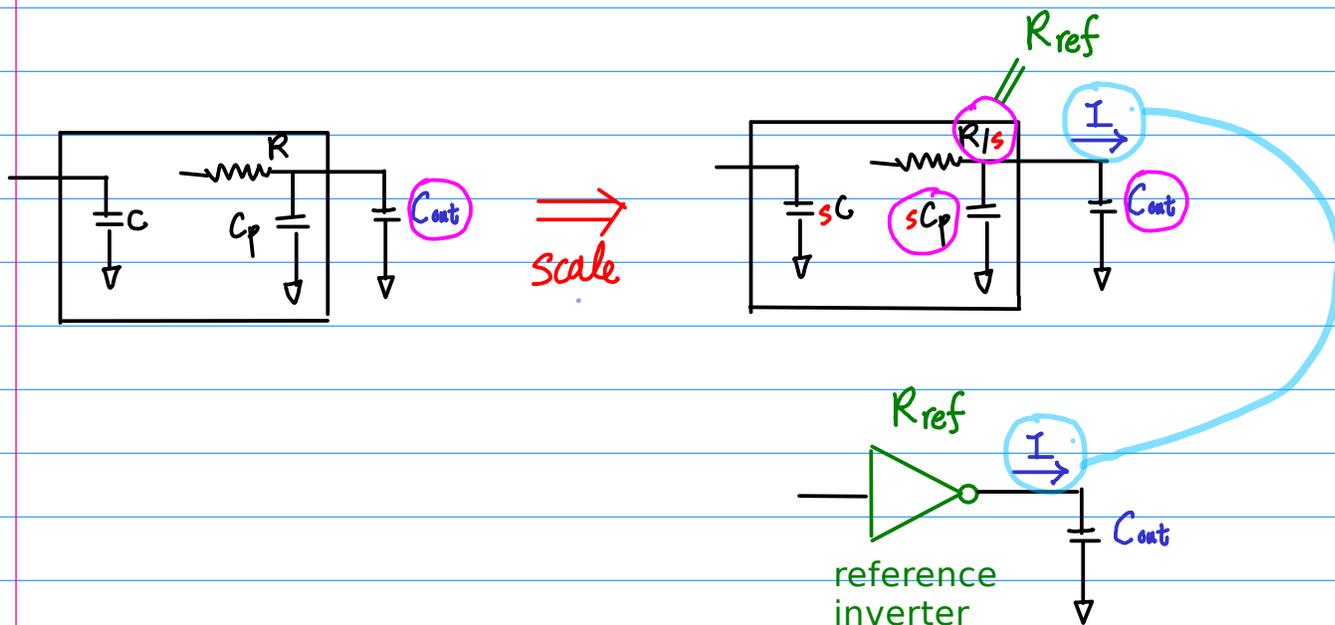
$$= \frac{R}{s} (s C_p + C_{out})$$



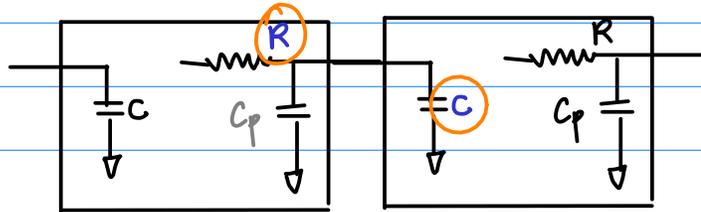
# \* Scaling Effects



increased  $C \rightarrow sC$   
 decreased  $R \rightarrow R/s$

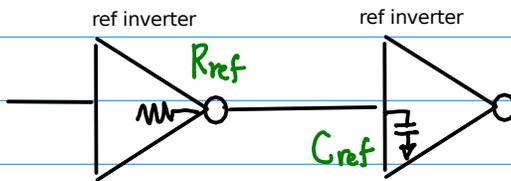


# \* Some time constants



series connection  
of the same gate  
under consideration

$$\tau = RC \quad C_p \ll C$$



series connection  
of the ref inverter

$$\tau_{ref} = R_{ref} C_{ref} \quad C_p \ll C_{ref}$$

# Logical Effort

Logical Effort  $g$  of a gate

the ratio of the input cap of the scaled gate  
to the input cap of the ref inverter

the gate is scaled to give the same output current  
as the ref inverter's output current

$$g = \frac{C_{in}}{C_{ref}}$$

$C_{in}$  after scaling

in order to make its output current

the same as the ref inverter's output current

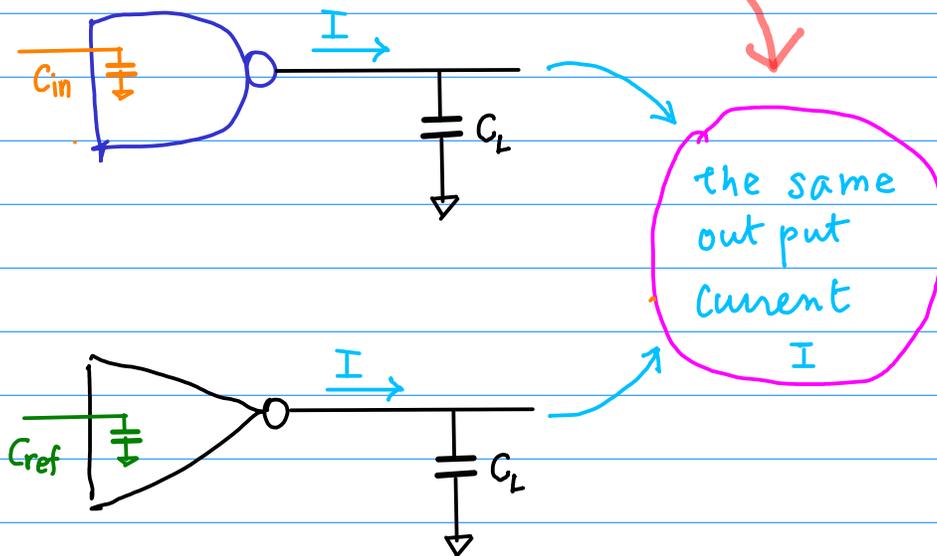
# ① Scaling information (how much bigger)

$$g = \frac{C_{in}}{C_{ref}} \quad \text{Logical Effort}$$

the input capacitance ratio  
to deliver the same output current  
of the reference gate

this ratio gives scaling information  
about how much bigger the gate should be  
to deliver the same output current  
of the reference gate

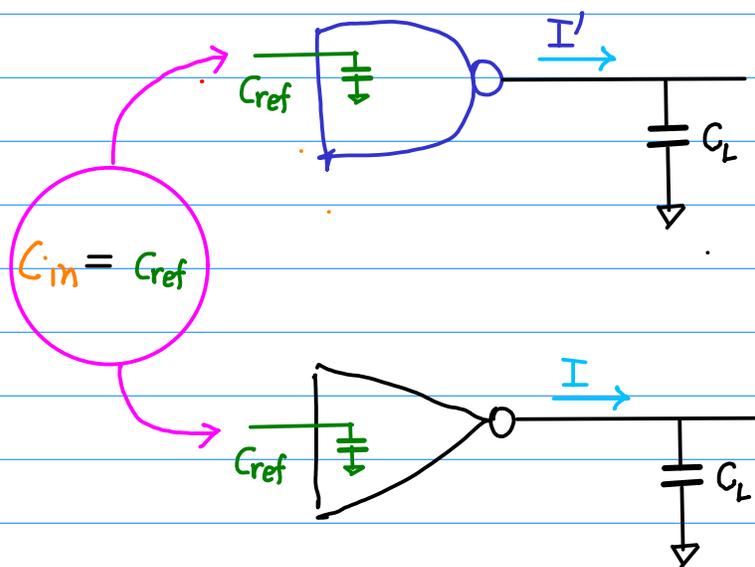
§ Scaled gate



## ② output drive reduction (how much worse)

how much worse a gate  
at producing output current  
as compared to an inverter

given that  
each input of the gate may have  
as much input capacitance as the inverter



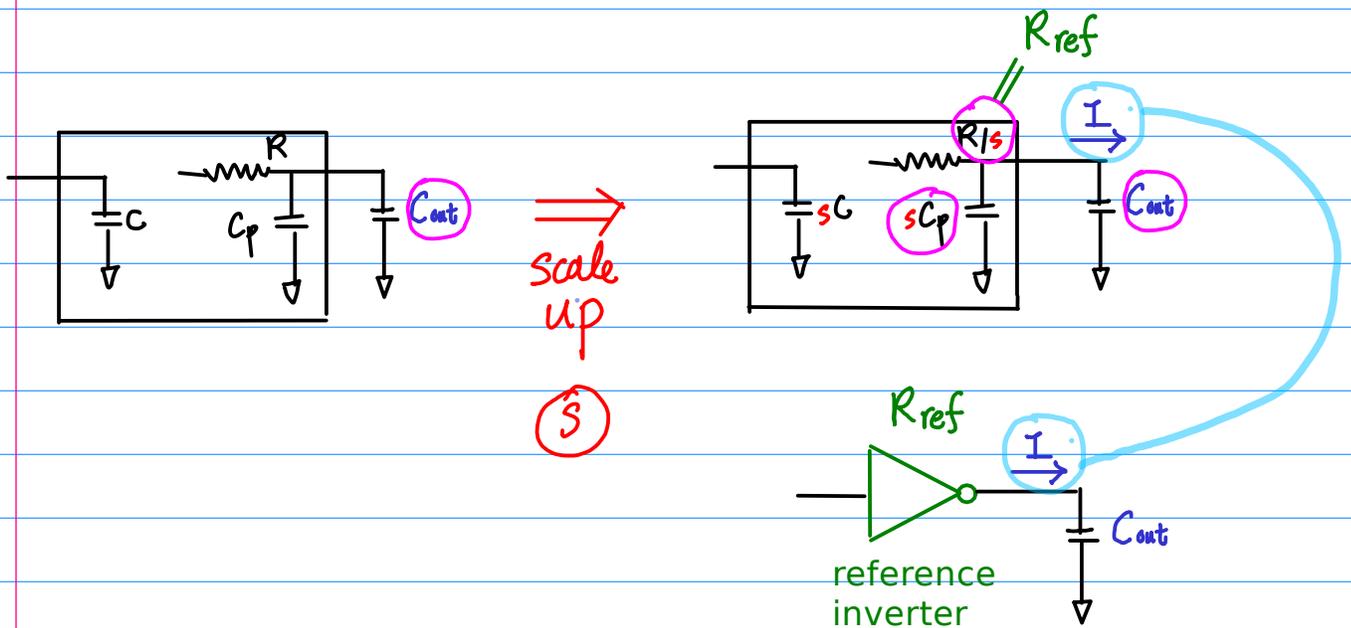
Resistive  
figure

$$\frac{I}{I'}$$

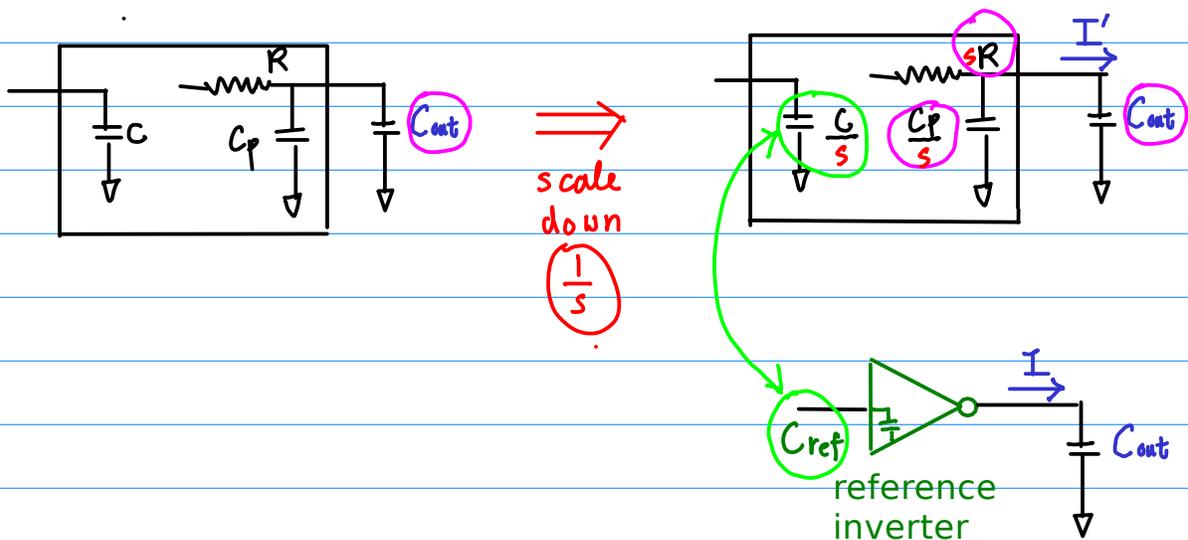
how worse

★  $g$ : output drive reduction  
when input cap sized same as inverter

① Scaling information (how much bigger)



② output drive reduction (how much worse)

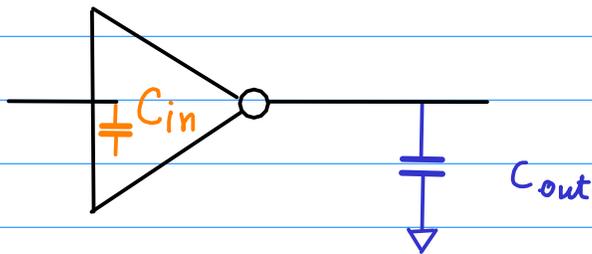


# Electrical Effort

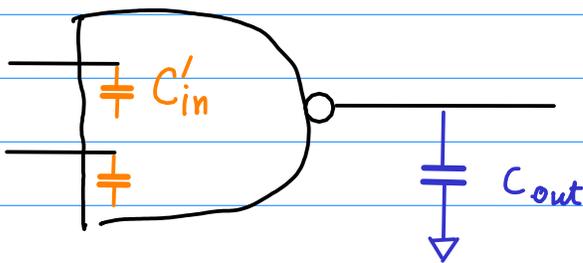
Electrical Effort : the output & input cap ratio

$$h = \frac{C_{out}}{C_{in}}$$

the ratio of the drive strength to drive  $C_{out}$  to the drive strength to drive its own capacitance  $C_{in}$



an inverter is driving  $C_{out}$

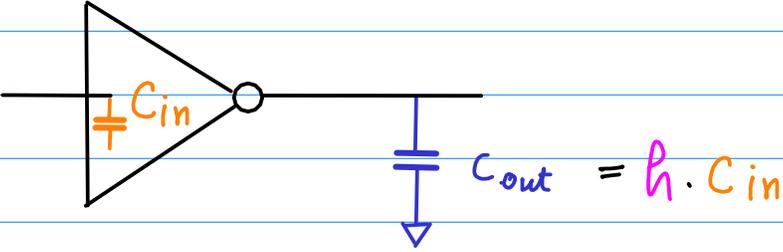


a NAND is driving  $C_{out}$

$C_{out}$  is  $h$  times larger than  $C_{in}$

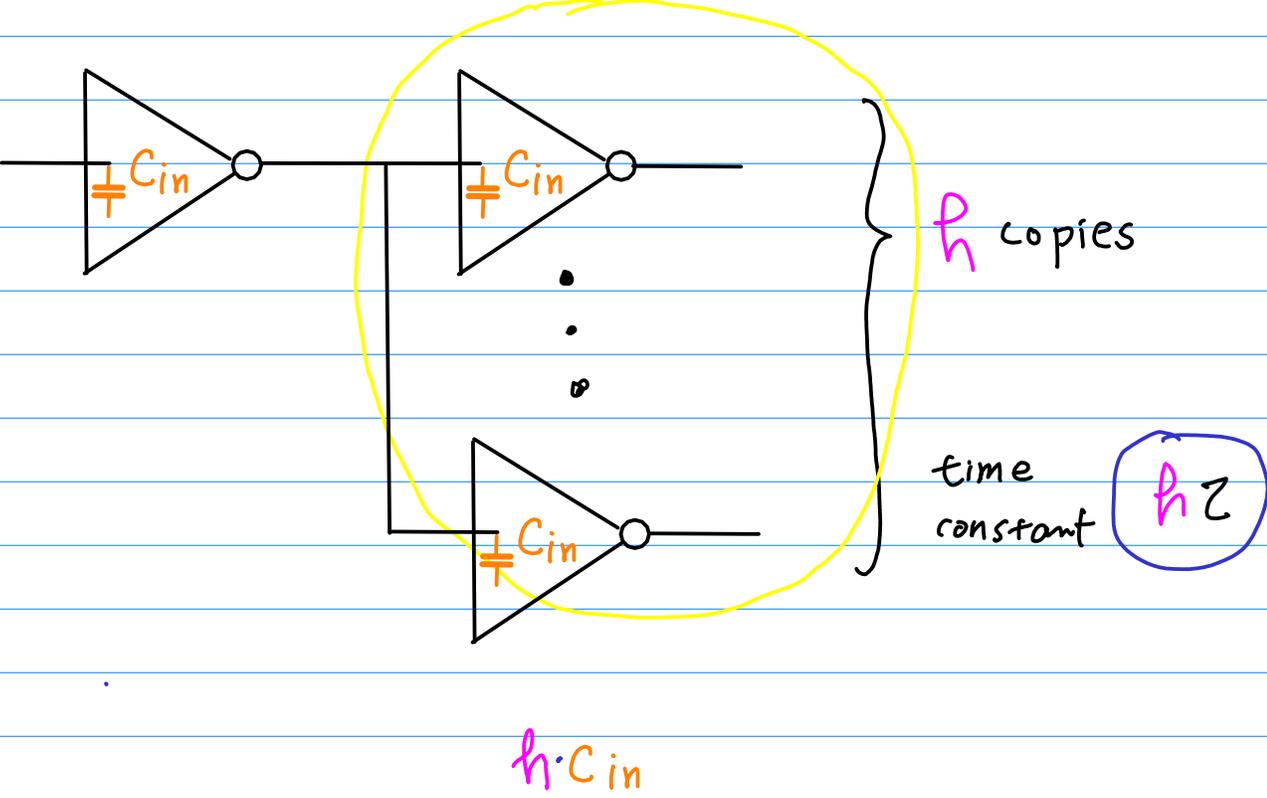
$$h = \frac{C_{out}}{C_{in}}$$

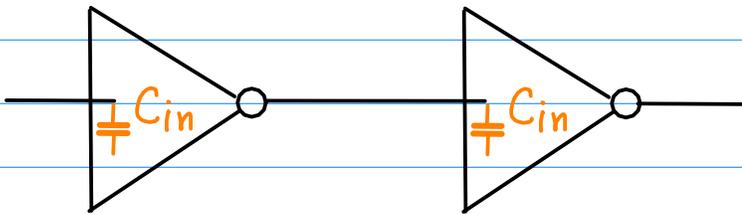
$C_{out}$  is  $h$  times larger than  $C_{in}$



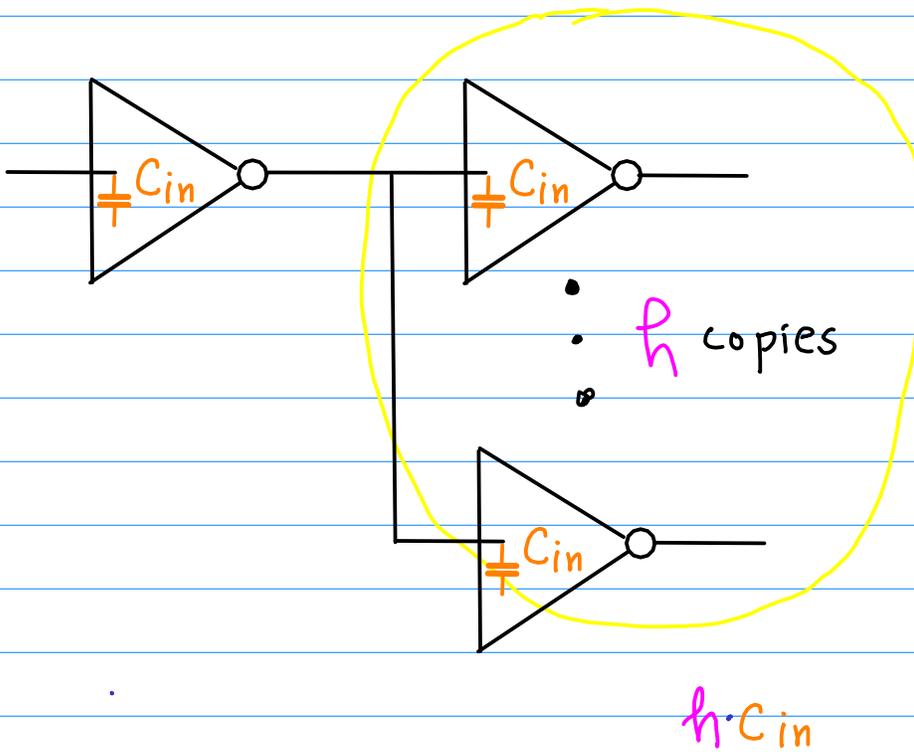
Electrical effort  $h$

$h$  copies of the same gate

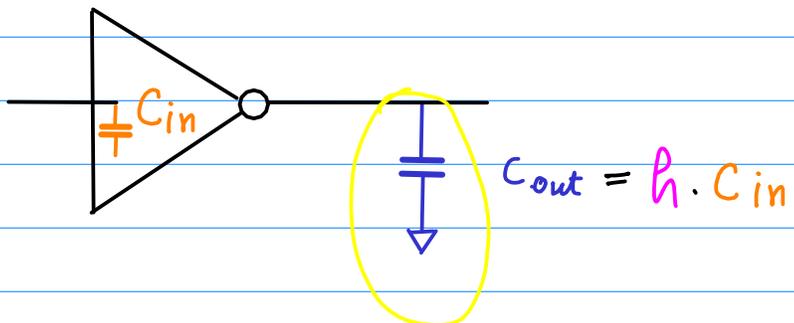




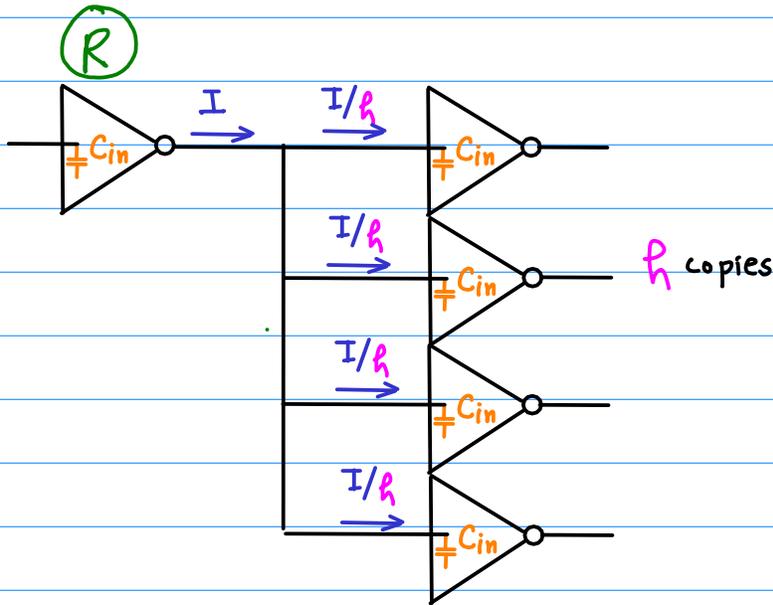
assume  
time constant  $\tau$



time constant  $h\tau$

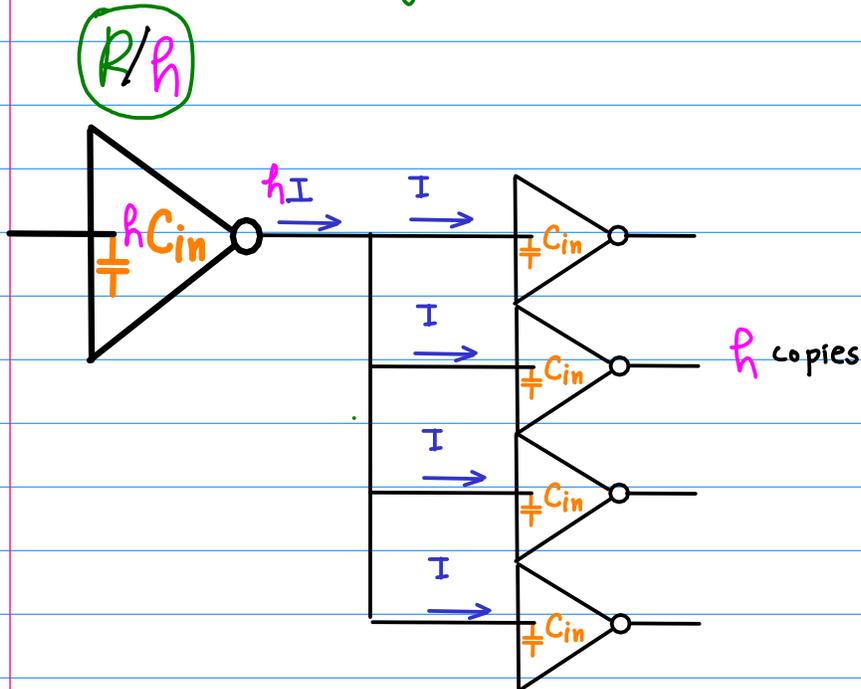


small drive strength



$$R \cdot h C_{in} = \tau$$

large drive strength



$$\frac{R}{h} \cdot h C_{in} = \tau$$

# Logical Effort: Designing for Speed on the Back of an Envelope

Ivan E. Sutherland  
Robert F. Sproull

9

the logical effort of an inverter is one

how much worse it is than an inverter  
at producing output current,  
given an equivalent amount of input capacitance

depends mainly on its circuit topology  
slightly on the electrical properties

captures the effect of the logic gate's topology  
on its ability to produce output current

independent of the size of the transistors

10

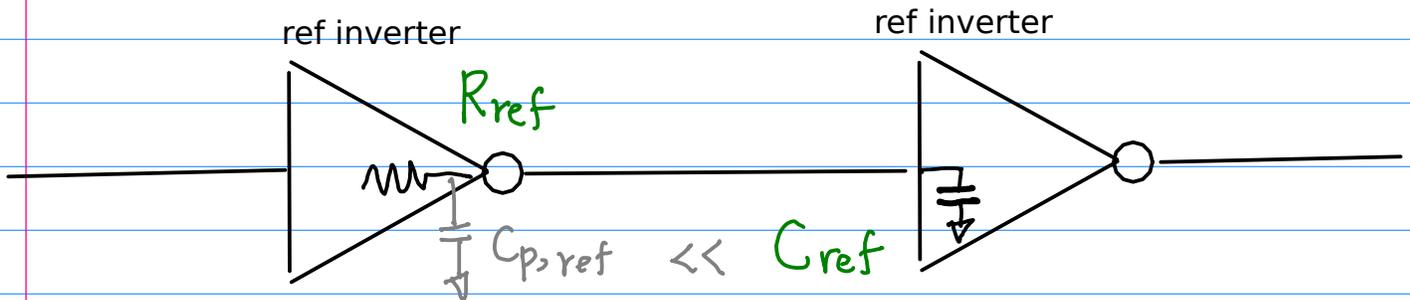
electrical effort describes

how the electrical environment of the logic gate  
affects performance and

how the size of the transistors in the gate  
determines its load-driving capability

as a ratio of transistor width rather than actual capacitances

# Normalized Delay



$$\tau = R_{ref} C_{ref}$$

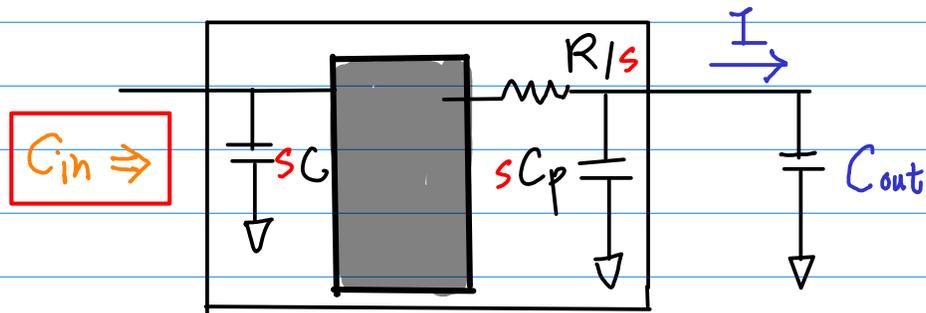
after scaling  
to get the same  $I$

$$d \propto \frac{R}{s} C_{out} + R C_p$$

$$\frac{d}{\tau} = \frac{d}{R_{ref} C_{ref}} \propto \frac{1}{s} \frac{R C_{out}}{R_{ref} C_{ref}} + \frac{R C_p}{R_{ref} C_{ref}}$$

normalized delay

# What is $g \cdot h$ ?



## Normalized Delay

$$\frac{d}{R_{ref} C_{ref}} \propto \frac{I}{s} \frac{R C_{out}}{R_{ref} C_{ref}} + \frac{R C_p}{R_{ref} C_{ref}}$$

$$\frac{I}{s} \frac{R C_{in}}{R_{ref} C_{ref}} \left( \frac{C_{out}}{C_{in}} \right)$$

$$= \frac{I}{s} \frac{R C_{in}}{R_{ref} C_{ref}} \left( \frac{C_{out}}{C_{in}} \right)$$

$$= \left( \frac{C_{in}}{C_{ref}} \right) \left( \frac{C_{out}}{C_{in}} \right)$$

$$= g \cdot h$$

$$R_{ref} = R/s$$

↳ scale for the same current I



## Normalized Delay

$$\frac{d}{R_{ref} C_{ref}} \propto \frac{1}{s} \frac{R C_{out}}{R_{ref} C_{ref}} + \frac{R C_p}{R_{ref} C_{ref}}$$

$$= \frac{1}{s} \frac{R C_{in}}{R_{ref} C_{ref}} \left( \frac{C_{out}}{C_{in}} \right)$$

$$= \frac{1}{s} \frac{R C_{in}}{R_{ref} C_{ref}} \left( \frac{C_{out}}{C_{in}} \right)$$

$$= \left( \frac{C_{in}}{C_{ref}} \right) \left( \frac{C_{out}}{C_{in}} \right)$$

$$= g \cdot h$$

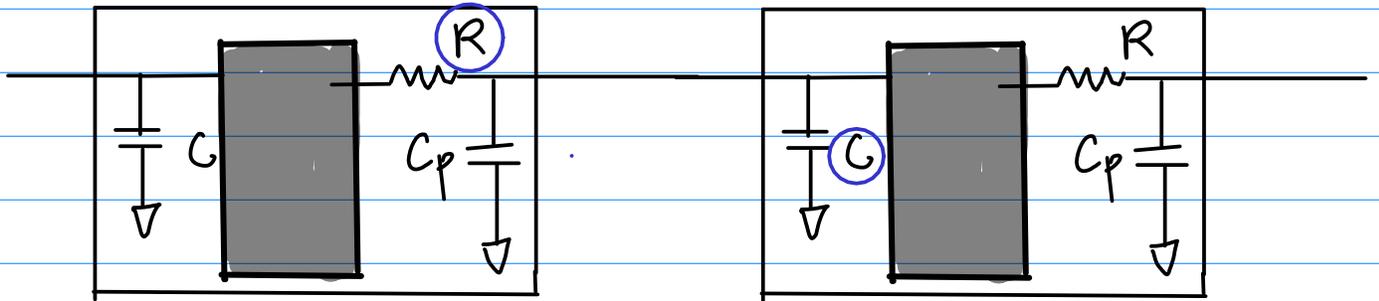
$$= \frac{1}{s} \frac{R s C}{R_{ref} C_{ref}} \left( \frac{C_{out}}{C_{in}} \right)$$

$$= \left( \frac{R C}{R_{ref} C_{ref}} \right) \left( \frac{C_{out}}{C_{in}} \right)$$

$$= \left( \frac{Z}{Z_{ref}} \right) \left( \frac{C_{out}}{C_{in}} \right)$$

$$C_{in} = s C$$

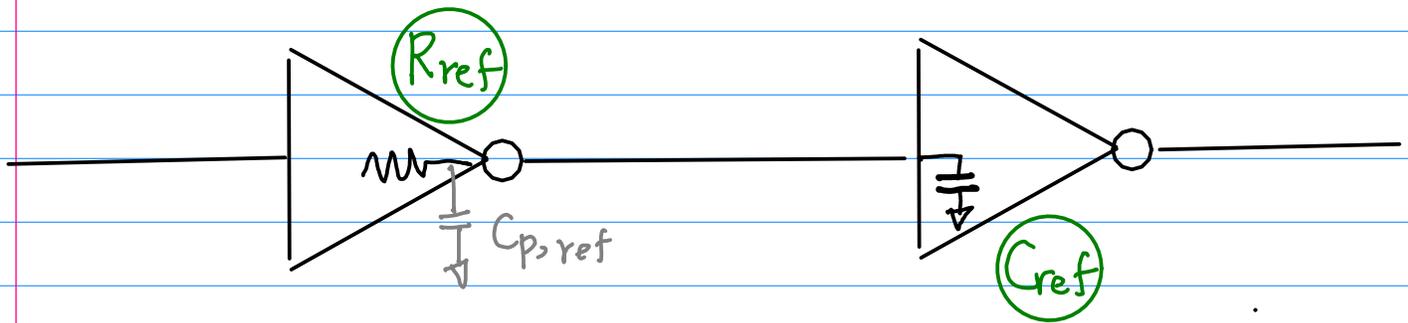
arbitrary gate *without scaling*



$$\tau = RC$$

time constant  
before scaling by S

ref inverter



$$C_{p,ref} \ll C_{ref}$$

ideal inverter :  
no parasitic delay

$$\tau_{ref} = R_{ref} C_{ref}$$

The 1st component of the normalized delay

$$\begin{aligned}g \cdot h &= \left( \frac{C_{in}}{C_{ref}} \right) \left( \frac{C_{out}}{C_{in}} \right) \\ &= \left( \frac{Z}{Z_{ref}} \right) \left( \frac{C_{out}}{C_{in}} \right) \\ &= \left( \frac{C_{out}}{C_{ref}} \right)\end{aligned}$$



$$\frac{d}{R_{ref} C_{ref}} \propto \frac{1}{s} \frac{R C_{out}}{R_{ref} C_{ref}} + \frac{R C_p}{R_{ref} C_{ref}}$$

# What is $p$ ?

parasitic delay  $(p)$

- delay due to internal parasitic capacitance

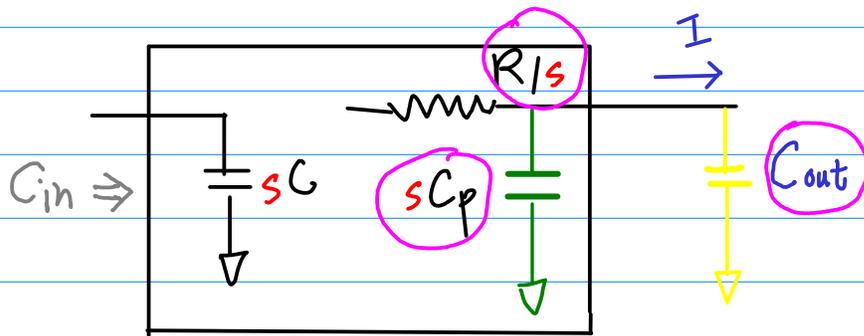
$sC_p$

- excluding external load cap

$C_{out}$

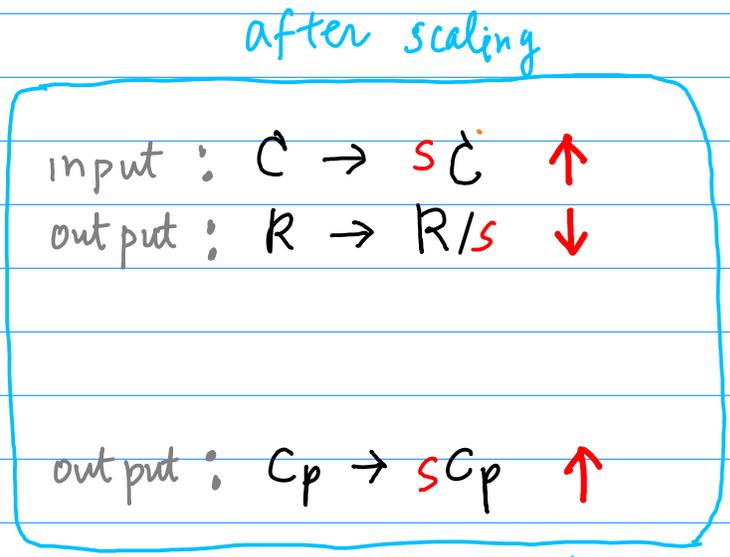
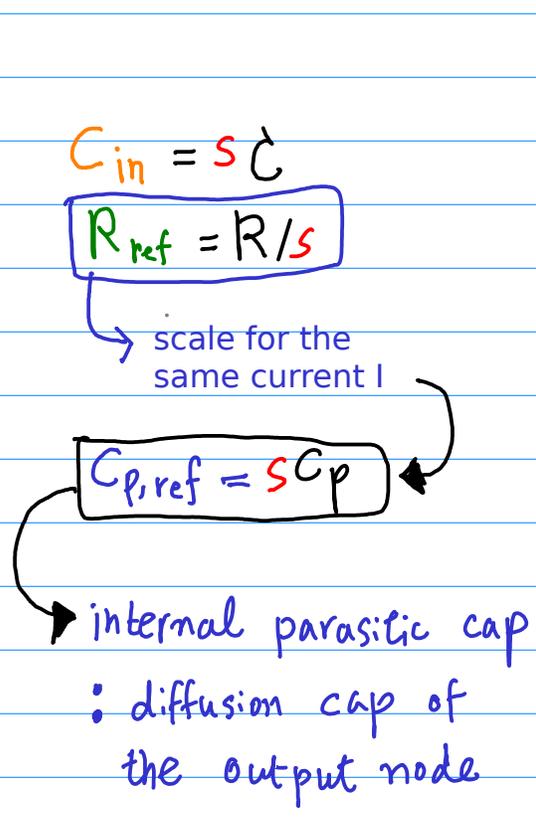
- count only diffusion capacitance of the output

- delay without output load



$$R/s \quad sC_p = RC_p$$

# \* Scaling Effects revisited



$$RC_p = \frac{1}{s} R \cdot sC_p$$

no change

## Normalized Delay

$$\frac{d}{R_{ref} C_{ref}} \propto \frac{1}{s} \frac{R C_{out}}{R_{ref} C_{ref}} + \frac{R C_p}{R_{ref} C_{ref}}$$

$$\frac{1}{s} \frac{R s C_p}{R_{ref} C_{ref}}$$

$$= \frac{1}{s} \frac{R}{R_{ref}} \left( \frac{C_{p,ref}}{C_{ref}} \right)$$

$$C_{in} = s C$$

$$R_{ref} = R/s$$

scale for the same current I

$$C_{p,ref} = s C_p$$

$$\left( \frac{\text{internal diffusion cap.}}{\text{gate cap of ref inv}} \right) = \left( \frac{C_{p,ref}}{C_{ref}} \right) = p$$

## Normalized Delay

$$\frac{d}{R_{ref} C_{ref}} \propto \frac{1}{s} \frac{R_{cont}}{R_{ref} C_{ref}} + \frac{R C_p}{R_{ref} C_{ref}}$$

$$\frac{1}{s} \frac{R}{R_{ref}} \frac{C_p}{C_{ref}}$$

$$= \frac{1}{s} \frac{R}{R_{ref}} \left( \frac{C_{p,ref}}{C_{ref}} \right)$$

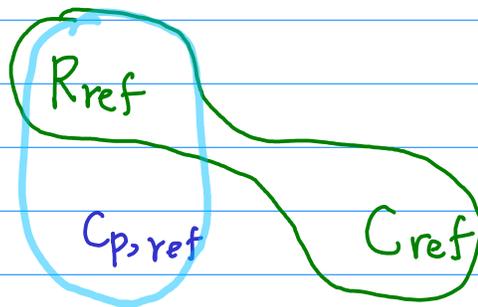
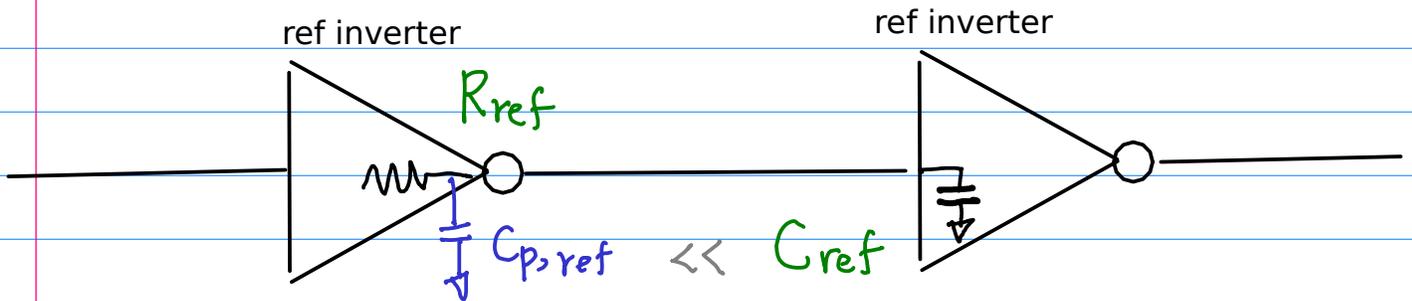
$$\left( \frac{\text{internal diffusion cap.}}{\text{gate cap of ref inv}} \right) = \left( \frac{C_{p,ref}}{C_{ref}} \right)$$

$$= P$$

$$= \frac{R C_p}{R_{ref} C_{ref}}$$

internal diff cap

$$\left( \frac{\text{RC value of a gate}}{\text{RC value of ref inv}} \right) = \frac{Z_{par}}{Z_{ref}}$$

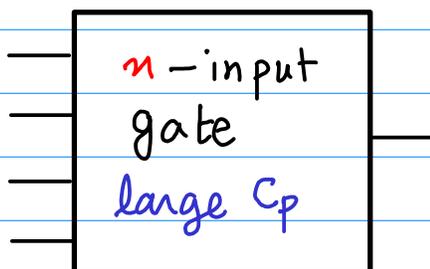


$$Z_{par} = R_{ref} C_{p,ref}$$

$$Z_{ref} = R_{ref} C_{ref}$$

$$P = \frac{Z_{par}}{Z_{ref}}$$

$$P_{ref} = 1$$



$$\eta P_{ref} = \eta$$

The 2nd component of the normalized delay

$$\begin{aligned} p &= \frac{R C_p}{R_{ref} C_{ref}} \\ &= \left( \frac{C_{p,ref}}{C_{ref}} \right) = \left( \frac{\text{internal diffusion cap.}}{\text{gate cap of ref inv}} \right) \\ &= \frac{Z_{par}}{Z_{ref}} = \left( \frac{\text{RC value of a gate}}{\text{RC value of ref inv}} \right) \end{aligned}$$

internal diff cap only

$$\frac{d}{R_{ref} C_{ref}} \propto \frac{1}{s} \frac{R C_{out}}{R_{ref} C_{ref}} + \frac{R C_p}{R_{ref} C_{ref}}$$

$$\frac{d}{R_{ref} C_{ref}} \propto \frac{1}{s} \frac{R_{out}}{R_{ref} C_{ref}} + \frac{R C_p}{R_{ref} C_{ref}}$$

$$= g \cdot h + p$$

$$g \cdot h = \left( \frac{C_{in}}{C_{ref}} \right) \left( \frac{C_{out}}{C_{in}} \right)$$

$$= \left( \frac{Z}{Z_{ref}} \right) \left( \frac{C_{out}}{C_{in}} \right)$$

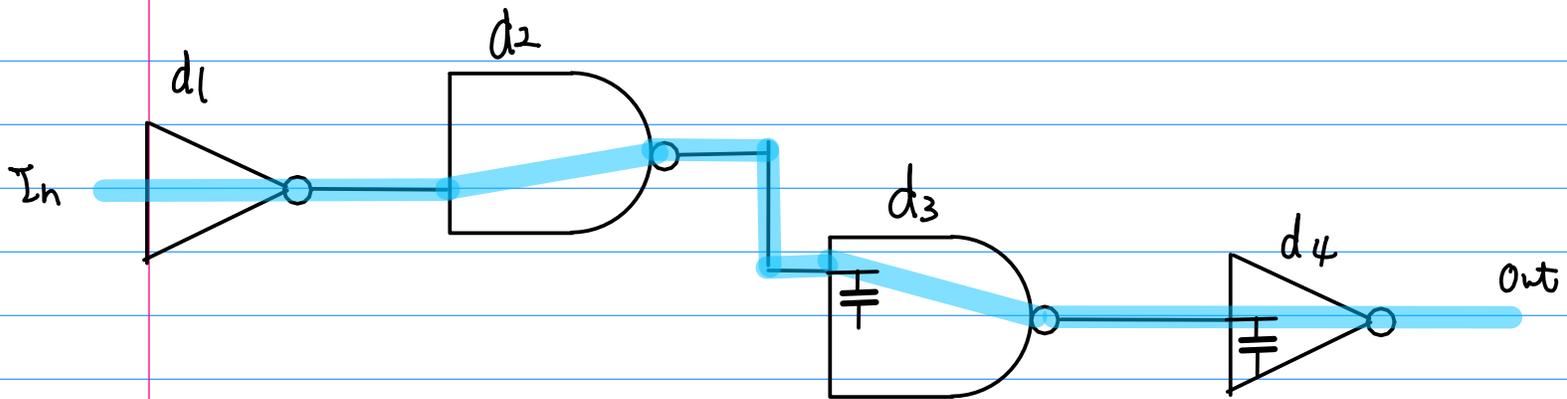
$$= \left( \frac{C_{out}}{C_{ref}} \right)$$

$$p = \frac{R C_p}{R_{ref} C_{ref}}$$

$$= \frac{Z_{par}}{Z_{ref}}$$

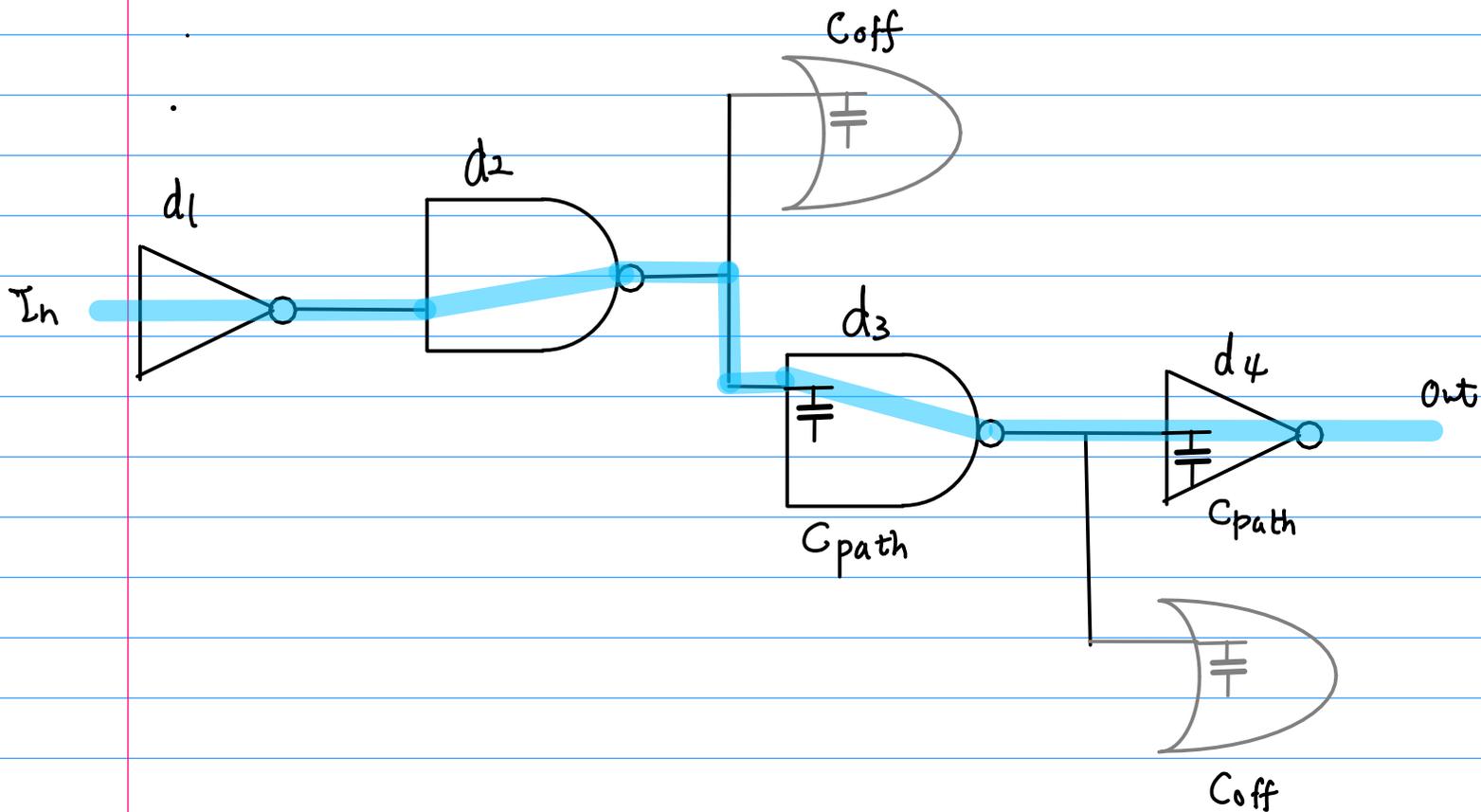
$$= \left( \frac{C_{p,ref}}{C_{ref}} \right)$$

# Path Delay



$$\sum d_i = d_1 + d_2 + d_3 + d_4$$

# Branch Effect



$$b_3 = \frac{C_{\text{path}} + C_{\text{off}}}{C_{\text{path}}}$$

$$b_4 = \frac{C_{\text{path}} + C_{\text{off}}}{C_{\text{path}}}$$

gate capacitance that are not in the path

but contribute to path delay

$$b > 1$$

all capacitance contributions that are off the main path

Path Branch Effort  $B = \prod b_i$

# Path Delay

$$d = g_h + p$$

$$d_i = g_i h_i + p_i$$

## Total Path Delay

$$D = \sum d_i = \sum (g_i h_i + p_i)$$

### Path Logical Effort

$$G = g_1 \cdot g_2 \cdots g_N$$

### Path Electrical Effort

$$H = h_1 \cdot h_2 \cdots h_N$$

### Path Effort

$$\begin{aligned} F = GH &= (g_1 h_1)(g_2 h_2) \cdots (g_N h_N) \\ &= f_1 f_2 \cdots f_N \end{aligned}$$

$$\underbrace{f_i = g_i \cdot h_i}$$

$$d = d_1 + d_2 + \dots + d_N$$

$$= (g_1 h_1 + P_1) + (g_2 h_2 + P) + \dots + (g_N h_N + P_N)$$

$$= (g_1 h_1 + g_2 h_2 + \dots + g_N h_N) + (P_1 + P_2 + \dots + P_N) = (f_1 + f_2 + \dots + f_N) + P$$

$$\geq N \sqrt[N]{(g_1 h_1)(g_2 h_2) \dots (g_N h_N)} + P = N \sqrt[N]{f_1 \cdot f_2 \dots f_N} + P$$

minimum when  $f_1 = f_2 = \dots = f_N = \hat{f}$

$$g_i h_i = \hat{f} \quad \text{constant}$$

$$d = (g_1 h_1 + g_2 h_2 + \dots + g_N h_N) + (P_1 + P_2 + \dots + P_N)$$

$$= (f_1 + f_2 + \dots + f_N) + P$$

$$\geq N \sqrt[N]{(g_1 h_1)(g_2 h_2) \dots (g_N h_N)} + P$$

$$= N \sqrt[N]{f_1 \cdot f_2 \dots f_N} + P$$

$$F = f_1 \cdot f_2 \dots f_N$$

$$G = g_1 \cdot g_2 \dots g_N$$

$$H = h_1 \cdot h_2 \dots h_N$$

$$P = P_1 + P_2 + \dots + P_N$$

$$F = G \cdot H$$

$$d \geq N \sqrt[N]{F} + P$$

$$\text{minimum when } \forall_i g_i h_i = \hat{f} = \sqrt[N]{F} = \sqrt[N]{GH}$$

$$D = \sum d_i = \sum (g_i h_i + p_i)$$

$$\geq N F^{\frac{1}{N}} + P$$

$$P = \sum p_i$$

$$h_i = \frac{f}{g_i}$$

$$P = \sum p_i \quad \text{sum of parasitic delay}$$

Logical Effort	$g = \frac{C_{in}}{C_{ref}}$	$G = \prod g_i$
Electrical Effort	$h = \frac{C_{out}}{C_{in}}$	$H = \frac{C_{out}(\text{path})}{C_{in}(\text{path})}$
Branching Effort	$x$	$B = \prod b_i$
Effort	$f = gh$	$F = GBH$
Effort Delay	$f$	$N F^{\frac{1}{N}}$
# of Stages	$1$	$N$
parasitic delay	$p$	$P = \sum p_i$
delay	$f + p$	$N F^{\frac{1}{N}} + P$